

EV550717305

Form PTO-1449  <b>LIST OF ART CITED BY APPLICANT</b> <small>(Use several sheets if necessary)</small>				U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2430		SERIAL NO. 10/705,371	
				APPLICANT Brian E. Cron					
				FILING DATE Nov. 10, 2003 [RCE filed herewith]		GROUP 3723			
U.S. PATENT DOCUMENTS									
Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date if Appropriate	
AD	AA	6,332,835 B1	12/01	Nishimura et al.		1	1		
	AB								
	AC								
	AD								
	AE								
	AF								
	AG								
	AH								
	AI								
	AJ								
	AK								
	AL								
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country		Class	Subclass	Translation	
								Yes	No
	AM								
	AN								
	AO								
	AP								
	AQ								
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)									
	AR								
	AS								
	AT								
EXAMINER	Anthony Ojini		DATE CONSIDERED	6/21/05					
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>									

JAN-26-2004 14:57

WELLS ST.JOHN, P.S.

5098383424 P.03/03

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. M723-313D	SERIAL NO. 10/723,870		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Rhee E. Cm			
				FILING DATE November 10, 2003	GROUP (Priority) 3723		
U.S. PATENT DOCUMENTS							
Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Applicable
<i>AD</i>	AA	5,518,030	08-1997	Whitney et al.	—	—	
	AB	5,770,322	07-1998	Whitney et al.	—	—	
	AC	5,611,948	01-2000	Lafaro	—	—	
	AD	6,017,423 D1	08-2001	Franco et al.	—	—	
	AE	6,224,461 D1	03-2001	Burton, Jr. et al.	—	—	
	AF	6,071,422 D1	12-2001	Mikellum et al.	—	—	
	AG	6,038,958 D1	08-2001	Olcott	—	—	
<i>AD</i>	AH	6,021,647 D1	03-2001	Shrock	—	—	
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translates Yes No
AM							
AN							
AO							
AP							
AQ							
OTHER REFERENCES (including AIA/US, TSM, PCT, etc., Page One)							
AR							
AS							
AT							
EXAMINER	<i>Anthony Ojini</i>			DATE CONSIDERED		<i>11/9/04</i>	
*EXAMINER'S Initial if reference considered, whether or not claim is in conformance with MPEP 627. Draw line through claims if not in conformance and not considered. Include copy of this form with next communication to applicant.							